

**Notice of References Cited**

Application/Control No.

10/007,474

Applicant(s)/Patent Under Reexam

Halasa et al.

Examiner

J. Pasterczyk

Art Unit

1755

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N	EP 0 877 034 A1	11/1998	EPO	Halasa et al.	----	----
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**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>
U	Chem. Abstracts 76:155173, referencing Fujio et al., Nippon Kagaku Kaishi, vol. 2, pp. 447-453 (1972).
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<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.